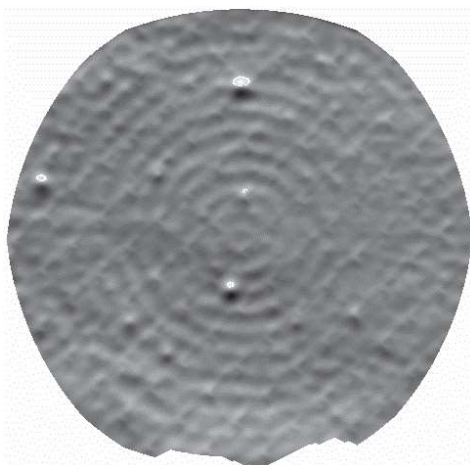


Wafer Surface Profiler

Fulfill all your needs with limited budget



- ◆ 非接觸式形貌量測
Non-contact measurement
- ◆ 高速擷取全域晶圓
600k point data in seconds
- ◆ 微米等級高解析度
Sub micro z resolution
- ◆ 3D彩色表面輪廓圖
3D colorful topography
- ◆ 晶圓膜層應力分析
Film stress analysis
- ◆ 晶圓形貌缺陷直讀
Surface protrusion inspection



#Bow, Warpage, Stress, Protrusion defect

